

# CLF1G0035-100P; CLF1G0035S-100P

Broadband RF power GaN HEMT

Rev. 1 — 10 December 2012

Objective data sheet

## 1. Product profile

### 1.1 General description

The CLF1G0035-100P and CLF1G0035S-100P are 100 W general purpose broadband GaN HEMTs usable from DC to 3.5 GHz.

**Table 1. CW and pulsed RF application information**

Typical RF performance at  $T_{case} = 25^\circ\text{C}$ ;  $I_{Dq} = 330 \text{ mA}$ ;  $V_{DS} = 50 \text{ V}$  in a class-AB broadband demo board.

Test signal	f (MHz)	P <sub>L</sub> (W)	G <sub>p</sub> (dB)	η <sub>D</sub> (%)
1-Tone CW	2500	100	12.8	51
	2600	100	12.7	52.4
	2700	100	12.3	50
	2800	100	11.7	49
	2900	100	11.5	49
	3000	100	10.5	47
1-Tone pulsed [1]	2500	100	14.2	52
	2600	100	14.4	54.4
	2700	100	14.1	52.5
	2800	100	13.7	51.5
	2900	100	13.6	51.8
	3000	100	12.7	50.1

[1] Pulsed RF;  $t_p = 100 \mu\text{s}$ ;  $\delta = 10 \%$ .

**Table 2. 2-Tone CW application information**

Typical 2-Tone performance at  $T_{case} = 25^\circ\text{C}$ ;  $I_{Dq} = 330 \text{ mA}$ ;  $V_{DS} = 50 \text{ V}$  in a class-AB broadband demo board.

Test signal	f (MHz)	P <sub>L(PEP)</sub> (W)	IMD3 (dBc)
2-Tone CW [1]	2500	20	-41.6
	2600	20	-43
	2700	20	-41.5
	2800	20	-41.3
	2900	20	-41.3
	3000	20	-40

[1] 2-Tone CW;  $\Delta f = 100 \text{ kHz}$ .



## 1.2 Features and benefits

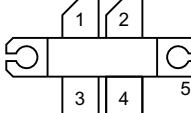
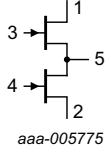
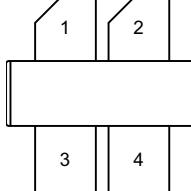
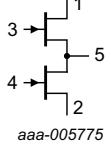
- Frequency of operation is from DC to 3.5 GHz
- 100 W general purpose broadband RF Power GaN HEMT
- Excellent ruggedness (VSWR = 10 : 1)
- High voltage operation (50 V)
- Thermally enhanced package

## 1.3 Applications

- |  |  |
|--|--|
| <ul style="list-style-type: none"> <li>■ Commercial wireless infrastructure (cellular, WiMAX)</li> <li>■ Radar</li> <li>■ Broadband general purpose amplifier</li> <li>■ Public mobile radios</li> </ul> | <ul style="list-style-type: none"> <li>■ Industrial, scientific, medical</li> <li>■ Jammers</li> <li>■ EMC testing</li> <li>■ Defense application</li> </ul> |
|--|--|

## 2. Pinning information

**Table 3. Pinning**

Pin	Description	Simplified outline	Graphic symbol
<b>CLF1G0035-100P (SOT1228A)</b>			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source	[1]	 
<b>CLF1G0035S-100P (SOT1228B)</b>			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source	[1]	 

[1] Connected to flange.

## 3. Ordering information

**Table 4. Ordering information**

Type number	Package			Version
	Name	Description		
CLF1G0035-100P	-	flanged ceramic package; 2 mounting holes; 4 leads		SOT1228A
CLF1G0035S-100P	-	earless flanged ceramic package; 4 leads		SOT1228B

## 4. Limiting values

**Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	150	V
$V_{GS}$	gate-source voltage		-8	+3	V
$I_{GF}$	forward gate current	external $R_G = 5 \Omega$	-	36	mA
$T_{stg}$	storage temperature		-65	+150	°C
$T_j$	junction temperature	measured via IR scan	-	250	°C

## 5. Thermal characteristics

**Table 6. Thermal characteristics**

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_j = 200 \text{ }^\circ\text{C}$	[1] <tbd>	K/W

[1]  $T_j$  is measured via IR scan with case temperature of 85 °C and power dissipation of <tbd> W.

## 6. Characteristics

**Table 7. DC characteristics** $T_{case} = 25 \text{ }^\circ\text{C}$ ; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = -7 \text{ V}; I_{DS} = <\text{tbd}> \text{ mA}$	150	-	-	V
$V_{GS(\text{th})}$	gate-source threshold voltage	$V_{DS} = 0.1 \text{ V}; I_{DS} = <\text{tbd}> \text{ mA}$	<tbd>	<tbd>	<tbd>	V
$I_{DSX}$	drain cut-off current	$V_{DS} = 10 \text{ V}; V_{GS} = 3 \text{ V}$	-	<tbd>	-	A
$g_{fs}$	forward transconductance	$V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}$	-	<tbd>	-	S

**Table 8. RF characteristics**Test signal: pulsed RF;  $t_p = 100 \mu\text{s}$ ;  $\delta = 10 \%$ ; RF performance at  $V_{DS} = 50 \text{ V}$ ;  $I_{Dq} = 330 \text{ mA}$ ;  $T_{case} = 25 \text{ }^\circ\text{C}$ ; unless otherwise specified in a class-AB production circuit.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f	frequency		2.5	-	3.0	GHz
$\eta_D$	drain efficiency	$P_L = 100 \text{ W}$	<tbd>	50	-	%
$G_p$	power gain	$P_L = 100 \text{ W}$	<tbd>	14	-	dB
$RL_{in}$	input return loss	$P_L = 100 \text{ W}$	-	-6	<tbd>	dB
$P_{\text{droop(pulse)}}$	pulse droop power	$P_L = 100 \text{ W}$	-	<tbd>	-	dB
$t_r$	rise time	$P_L = 100 \text{ W}$	-	<tbd>	-	ns
$t_f$	fall time	$P_L = 100 \text{ W}$	-	<tbd>	-	ns

## 7. Application information

**Table 9. CW and pulsed RF application information**

Typical RF performance at  $T_{case} = 25^\circ\text{C}$ ;  $I_{Dq} = 330 \text{ mA}$ ;  $V_{DS} = 50 \text{ V}$  in a class-AB broadband demo board.

Test signal	f (MHz)	P <sub>L</sub> (W)	G <sub>p</sub> (dB)	η <sub>D</sub> (%)
1-Tone CW	2500	100	12.8	51
	2600	100	12.7	52.4
	2700	100	12.3	50
	2800	100	11.7	49
	2900	100	11.5	49
	3000	100	10.5	47
1-Tone pulsed [1]	2500	100	14.2	52
	2600	100	14.4	54.4
	2700	100	14.1	52.5
	2800	100	13.7	51.5
	2900	100	13.6	51.8
	3000	100	12.7	50.1

[1] Pulsed RF;  $t_p = 100 \mu\text{s}$ ;  $\delta = 10 \%$ .

**Table 10. 2-Tone CW application information**

Typical 2-Tone performance at  $T_{case} = 25^\circ\text{C}$ ;  $I_{Dq} = 330 \text{ mA}$ ;  $V_{DS} = 50 \text{ V}$  in a class-AB broadband demo board.

Test signal	f (MHz)	P <sub>L(PEP)</sub> (W)	IMD3 (dBc)
2-Tone CW [1]	2500	20	-41.6
	2600	20	-43
	2700	20	-41.5
	2800	20	-41.3
	2900	20	-41.3
	3000	20	-40

[1] 2-Tone CW;  $\Delta f = 100 \text{ kHz}$ .

### 7.1 Ruggedness in class-AB operation

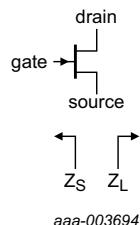
The CLF1G0035-100P and CLF1G0035S-100P are capable of withstanding a load mismatch corresponding to  $VSWR = 10 : 1$  through all phases under the following conditions:  $V_{DS} = 50 \text{ V}$ ;  $P_L = 100 \text{ W}$  (pulsed RF),  $f = 2500 \text{ MHz}$ .

### 7.2 Load pull impedance information

The measured half section load pull impedances are shown below. Impedance reference plane defined at device leads at each half section. Measurements performed with NXP test fixtures. Test temperature set at  $25^\circ\text{C}$  with a pulsed CW signal;  $t_p = 100 \mu\text{s}$ ;  $\delta = 10 \%$ ; RF performance at  $V_{DS} = 50 \text{ V}$ ;  $I_{Dq} = 150 \text{ mA}$ .

**Table 11. Typical impedance***Typical values unless otherwise specified.*

<b>f</b> <b>MHz</b>	<b>Z<sub>S</sub></b> <b>Ω</b>	<b>Z<sub>L</sub> (maximum P<sub>L(M)</sub>)</b> <b>Ω</b>	<b>Z<sub>L</sub> (maximum η<sub>D</sub>)</b> <b>Ω</b>
500	6.4 + 4j	9.7 + 7j	10 + 5j
1000	1.9 + 2.2j	9.1 + 12.4j	10 + 6j
2000	1.9 – 2.9j	5 + 4.1j	6.6 + 1.4j
2500	2.1 – 6.3j	3.6 + 0.75j	4.5 – 0.4j
3000	2.5 – 9j	3.9 – 1.2j	5.8 – 1.8j
3500	2.9 – 14j	6.6 – 2j	5.8 – 3j

**Fig 1. Definition of transistor impedance**

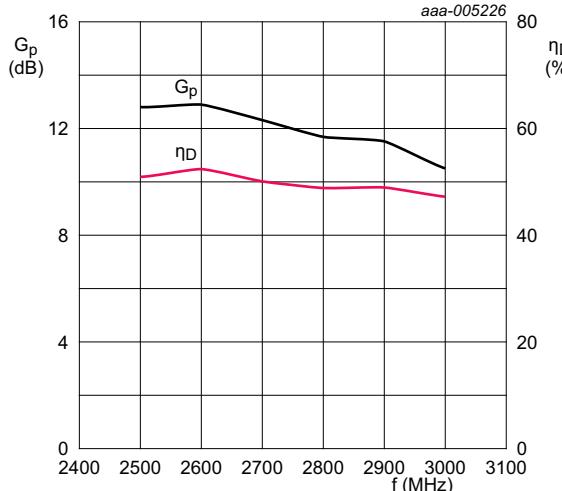
$Z_S$  is the measured source pull impedance presented to the device.  $Z_L$  is the measured load pull impedance presented to the device.

## 8. Test information

### 8.1 Graphical data

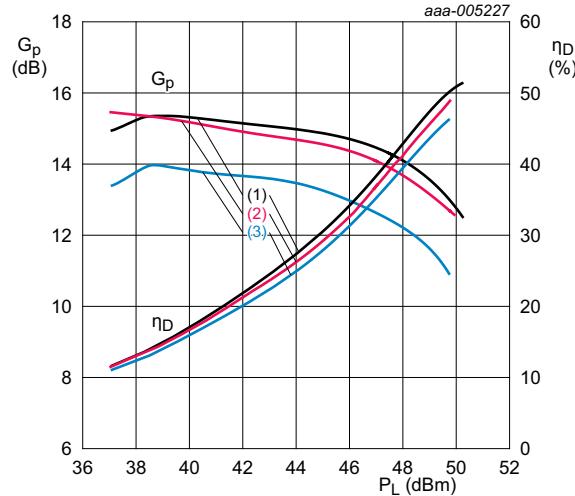
The following figures are measured in a broadband amplifier demo board from 2500 MHz to 3000 MHz.

#### 8.1.1 1-Tone CW RF performance



$V_{DS} = 50$  V;  $I_{Dq} = 330$  mA;  $P_L = 100$  W.

**Fig 2. Power gain and drain efficiency as function of frequency; typical values**

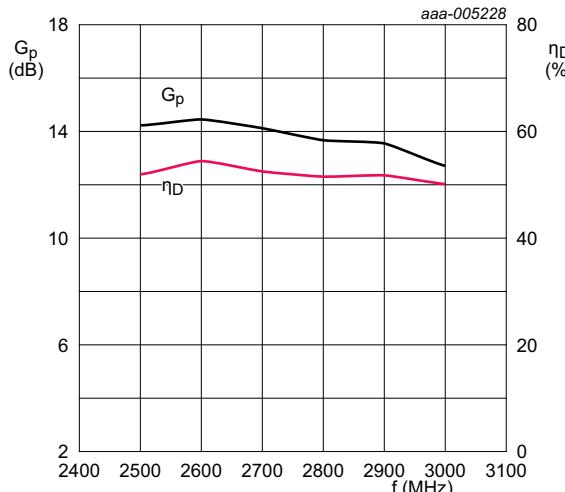


$V_{DS} = 50$  V;  $I_{Dq} = 330$  mA.

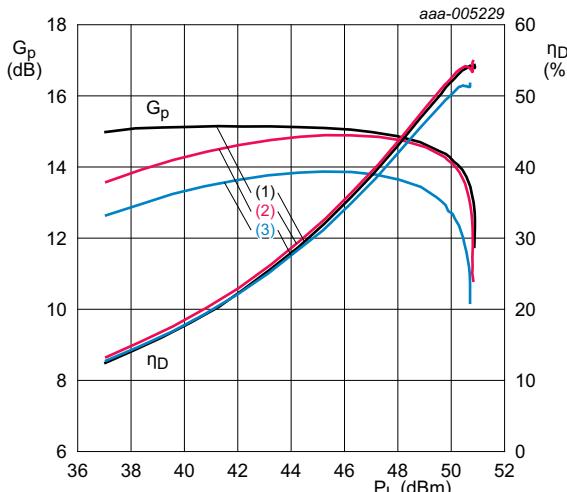
- (1)  $f = 2500$  MHz
- (2)  $f = 2700$  MHz
- (3)  $f = 3000$  MHz

**Fig 3. Power gain and drain efficiency as a function of output power; typical values**

### 8.1.2 1-Tone pulsed RF performance



$V_{DS} = 50$  V;  $I_{Dq} = 330$  mA;  $P_L = 100$  W.



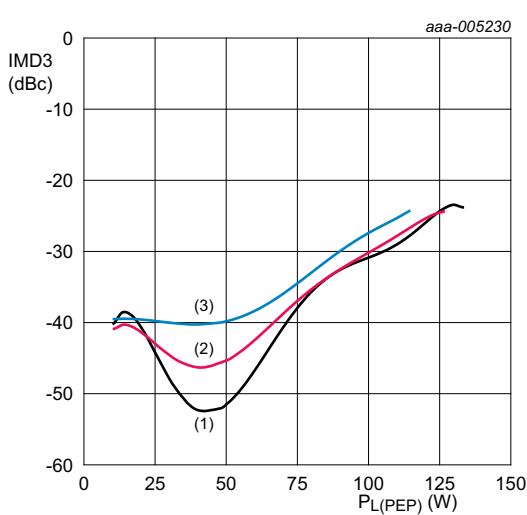
$V_{DS} = 50$  V;  $I_{Dq} = 330$  mA.

- (1)  $f = 2500$  MHz
- (2)  $f = 2700$  MHz
- (3)  $f = 3000$  MHz

**Fig 4. Power gain and drain efficiency as function of frequency; typical values**

**Fig 5. Power gain and drain efficiency as function of output power; typical values**

### 8.1.3 2-Tone CW performance



$\Delta f = 100$  kHz;  $V_{DS} = 50$  V;  $I_{Dq} = 330$  mA.

- (1)  $f = 2500$  MHz
- (2)  $f = 2700$  MHz
- (3)  $f = 3000$  MHz

**Fig 6. Third-order intermodulation distortion as a function of peak envelope power load power; typical values**

## 9. Package outline

Flanged ceramic package; 2 mounting holes; 4 leads

SOT1228A

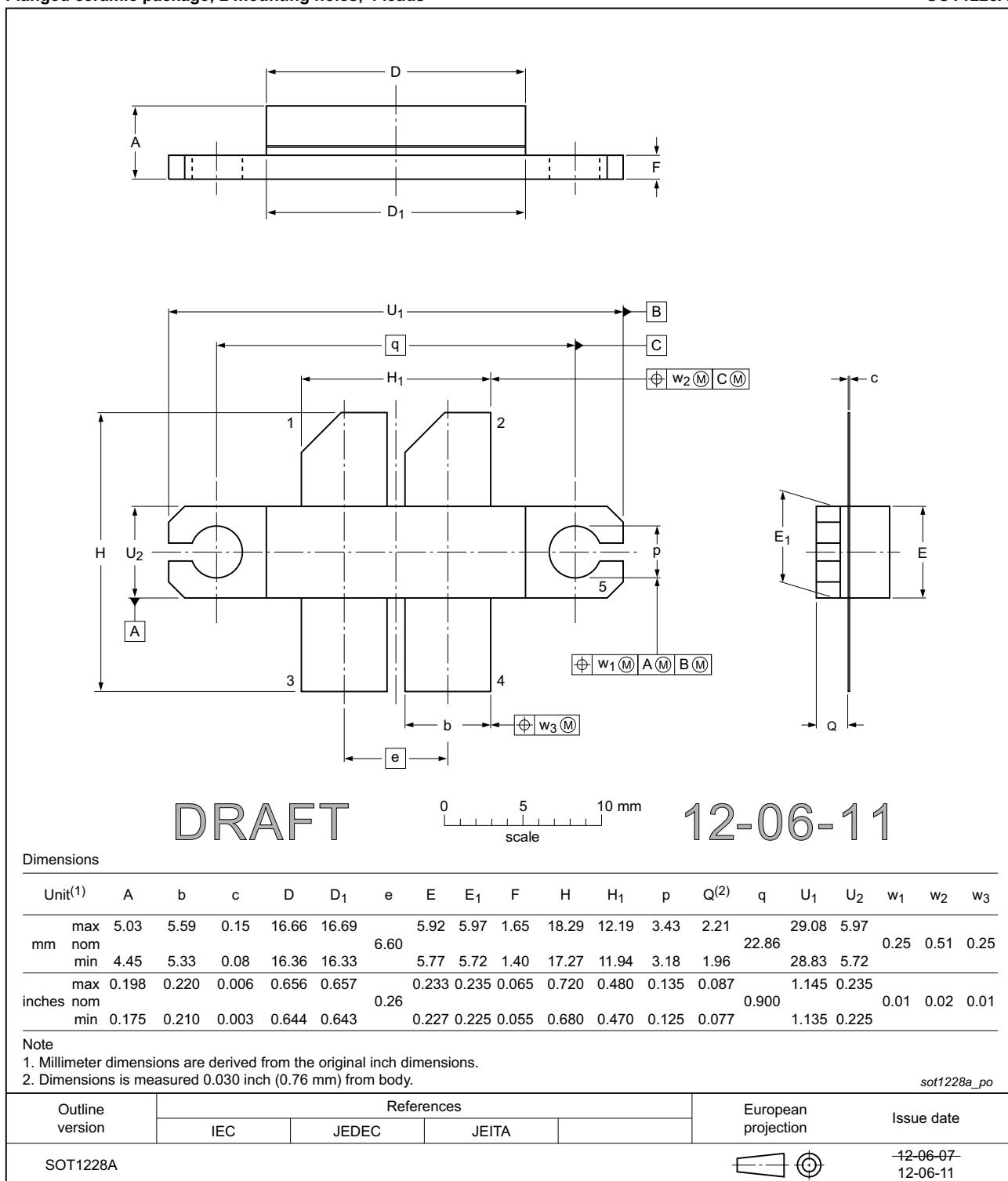
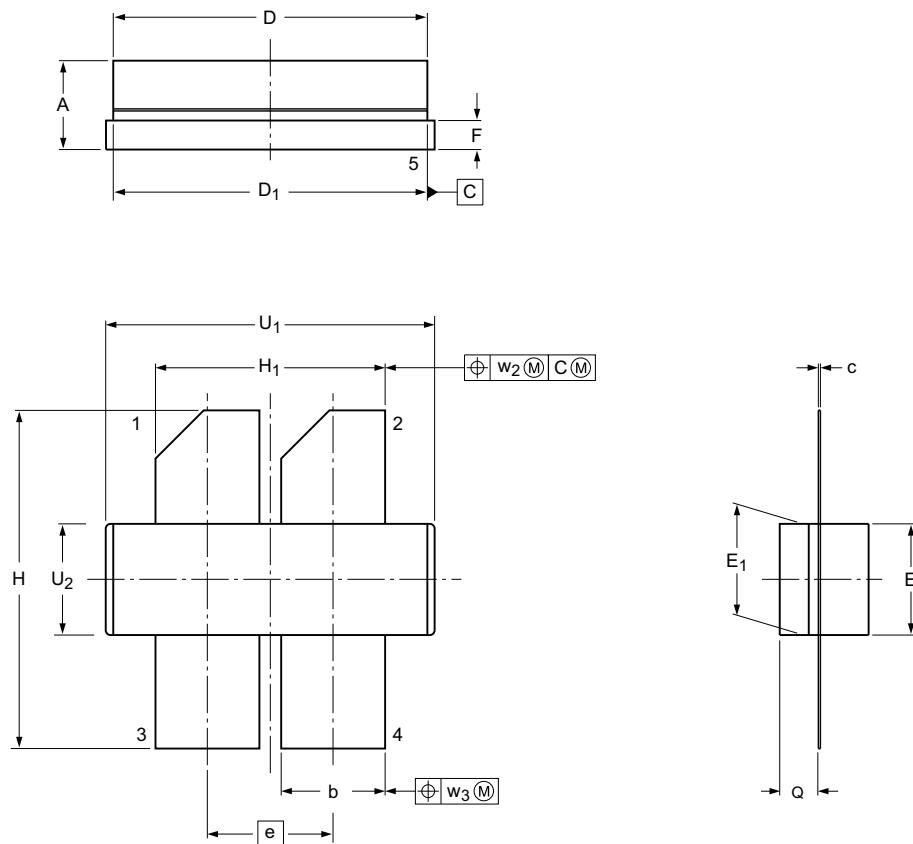


Fig 7. Package outline SOT1228A

## Earless flanged ceramic package; 4 leads

SOT1228B



DRAFT

0 5 10 mm  
scale

12-06-11

## Dimensions

Unit <sup>(1)</sup>	A	b	c	D	D <sub>1</sub>	e	E	E <sub>1</sub>	F	H	H <sub>1</sub>	Q <sup>(2)</sup>	U <sub>1</sub>	U <sub>2</sub>	w <sub>2</sub>	w <sub>3</sub>
mm	max 5.03	5.59	0.15	16.66	16.69		5.92	5.97	1.65	18.29	12.19	2.21	17.40	5.97		
	nom					6.60									0.51	0.25
	min 4.45	5.33	0.08	16.36	16.33		5.77	5.72	1.40	17.27	11.94	1.96	17.15	5.72		
inches	max 0.198	0.220	0.006	0.656	0.657		0.233	0.235	0.065	0.720	0.480	0.087	0.685	0.235		
	nom					0.26									0.02	0.01
	min 0.175	0.210	0.003	0.644	0.643		0.227	0.225	0.055	0.680	0.470	0.077	0.675	0.225		

## Note

1. Millimeter dimensions are derived from the original inch dimensions.
2. Dimensions are measured 0.030 inch (0.76 mm) from body.

sot1228b\_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
SOT1228B						12-06-07 12-06-11

Fig 8. Package outline SOT1228B

## 10. Handling information

### 10.1 ESD Sensitivity

**Table 12. ESD sensitivity**

ESD model	Class
Human Body Model (HBM); According JEDEC standard JESD22-A114F	1B <a href="#">[1]</a>

[1] Classification 1B is granted to any part that passes after exposure to an ESD pulse of 500 V, but fails after exposure to an ESD pulse of 1000 V.

## 11. Abbreviations

**Table 13. Abbreviations**

Acronym	Description
CW	Continuous Wave
EMC	ElectroMagnetic Compatibility
ESD	ElectroStatic Discharge
GaN	Gallium Nitride
HEMT	High Electron Mobility Transistor
VSWR	Voltage Standing-Wave Ratio
WiMAX	Worldwide Interoperability for Microwave Access

## 12. Revision history

**Table 14. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
CLF1G0035-100P_1G0035S-100P v.1	20121210	Objective data sheet	-	-

## 13. Legal information

### 13.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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